

CLAIMS

1 1. A apparatus for interfacing a socket to a testing apparatus which
2 comprises:
3 a base member;
4 a first electrically conductive contact member being removably attachable
5 to the base member;
6 the first contact member having a first portion thereof sized and shaped to
7 engage an electrical contact on the testing apparatus and a second portion thereof
8 sized and shaped to engage a second contact member;
9 a second contact member having a first portion thereof sized and shaped
10 to engage the second portion of the first contact member; and
11 the second contact member being removably and electrically connectable
12 to the socket.

1 2. The apparatus of claim 1 further comprising:
2 a plurality of first and a plurality of second contacts, each arranged in pairs
3 of sets; and
4 each of the second contacts being removably attachable to a separate
5 electrical connection with the socket.

1 3. The apparatus of claim 2 wherein the first contacts are removably
2 attachable to the base member by at least one clamp mechanism and connections
3 between first and second contacts are facilitated by the clamp mechanism.

1 4. The apparatus of claim 1 wherein the first contact is removably
2 attachable to the base member by a clamp mechanism and the connection between the
3 first and the second contacts is facilitated by the clamp mechanism.

1 5. The apparatus of claim 4 further comprising a socket base having
2 at least one pin receptacle electrically connected to the second contact where the pin
3 receptacle is sized and shaped to removably engage a pin in the socket.

1 6. The apparatus of claim 3 further comprising a socket base having
2 a plurality of pin receptacles each electrically connected to a separate one of the
3 plurality of second contacts, where each pin receptacle is sized and shaped to
4 removably engage a pin in the socket.

1 7. The apparatus of claim 2 further comprising a socket base having
2 a plurality of pin receptacles each electrically connected to a separate one of the
3 plurality of second contacts, where each pin receptacle is sized and shaped to
4 removably engage a pin in the socket.

1 8. The apparatus of claim 1 further comprising a socket base having
2 at least one pin receptacle electrically connected to the second contact where the pin
3 receptacle is sized and shaped to removably engage a pin in the socket.

1 9. A system for testing an electronic device which comprises:
2 a testing apparatus including a test fixture for interfacing with electronic
3 devices to be tested;
4 a base member;
5 a first electrically conductive contact member being removably attachable
6 to the base member;
7 the first contact member having a first portion thereof sized and shaped to
8 engage an electrical contact on the test fixture and a second portion thereof sized and
9 shaped to engage a second contact member;
10 a second contact member having a first portion thereof sized and shaped
11 to engage the second portion of the first contact member; and

12 the second contact member being removably and electrically connectable
13 to the socket.

1 10. The system of claim 9 further comprising:
2 a plurality of first and a plurality of second contacts, each arranged in pairs
3 of sets; and
4 each of the second contacts being removably attachable to a separate
5 electrical connection with the socket.

1 11. The system of claim 10 wherein the first contacts are removably
2 attachable to the base member by at least one clamp mechanism and connections
3 between first and second contacts are facilitated by the clamp mechanism.

1 12. The system of claim 9 wherein the first contact is removably
2 attachable to the base member by a clamp mechanism and the connection between the
3 first and the second contacts is facilitated by the clamp mechanism.

1 13. The system of claim 12 further comprising a socket base having at
2 least one pin receptacle electrically connected to the second contact where the pin
3 receptacle is sized and shaped to removably engage a pin in the socket.

1 14. The system of claim 11 further comprising a socket base having a
2 plurality of pin receptacles each electrically connected to a separate one of the plurality
3 of second contacts, where each pin receptacle is sized and shaped to removably
4 engage a pin in the socket.

1 15. The system of claim 10 further comprising a socket base having a
2 plurality of pin receptacles each electrically connected to a separate one of the plurality

3 of second contacts, where each pin receptacle is sized and shaped to removably
4 engage a pin in the socket.

1 16. The system of claim 9 further comprising a socket base having at
2 least one pin receptacle electrically connected to the second contact where the pin
3 receptacle is sized and shaped to removably engage a pin in the socket.

1 17. A method for interfacing a relatively small number of electrical
2 devices to be tested with a high volume testing device comprising the acts of:
3 attaching a first set of contacts to the testing device;
4 removably fixing a second set of contacts in contact with the first set of
5 contacts;
6 attaching a removable electrical socket to the second set of contacts; and
7 placing a device to be tested within the socket.